

Notice of References Cited	Application/Control No. 10/511,749		Applicant(s)/Patent Under Reexamination ADACHI, DAISUKE	
	Examiner BRITTANY RAYMOND		Art Unit 1722	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0076889	04-2004	Huang et al.	430/005
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rieger, M.L. et al. "Image Quality Enhancements for Raster Scan Lithography." Proceedings of SPIE, Vol. 922, Optical/Laser Microlithography, March 1988, p.55-64.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.